

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Docket Number (Optional) <b>TWI-11120</b>		Application Number <b>NEW</b>	
				Applicant(s) <b>John J. Sidorowich</b>			
				Filing Date <b>HEREWITH</b>		Group Art Unit <b>Unknown</b>	

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
SN	*AA	4,999,509	03/12/1991	Wada et al.	250	559.27	03/26/1990
SN	*AB	5,148,513	09/15/1992	Koza et al.	706	13	09/18/1990
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	*AJ	5,541,848	07/30/1996	McCormack	700	213	12/15/1994
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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

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SN	*AT	R.A. Sequeira et al., "Automating the parameterization of mathematical models using genetic algorithms," <i>Computer and Electronics in Agriculture</i> , 1994, Vol. 11, pp. 265-290.
↑	*AU	E. Michielssen et al., "Optimal multilayer filter design using real coded genetic algorithms," <i>IEE Proceedings-J</i> , Dec. 1992, Vol. 139, No. 6, pp. 413-420.
	*AV	T. Eisenhamer et al., "Optimization of interference filters with genetic algorithms applied to silver-based heat mirrors," <i>Applied Optics</i> , Nov. 1, 1993, Vol. 32, No. 31, pp. 6310-6315.
	*AW	S. Martin et al., "Simulated Darwinian evolution of homogeneous multilayer systems: a new method for optical coatings design," <i>Optics Communications</i> , Sep. 1, 1994, Vol. 110, No. 5/6, pp. 503-506.
	*AX	K. Rabinovitch et al., "Genetic algorithm and thin-film design," <i>Proceedings SPIE</i> , July 1994, Vol. 2262, pp. 163-174.
	*AY	S. Martin et al., "Synthesis of optical multilayer systems using genetic algorithms," <i>Applied Optics</i> , May 1, 1995, Vol. 34, No. 13, pp. 2247-2254.
	*AZ	T. Bäck et al., "Evolution Strategies for Mixed-Integer Optimization of Optical Multilayer Systems," <i>Proceedings Fourth Annual Conference on Evolutionary Programming</i> , 1995, pp. 33-51.
↓	*BA	D.J. Mikulin et al., "Fitting reflectivity data from liquid crystal cells using genetic algorithms," <i>Liquid Crystals</i> , 1997, Vol. 22, No. 3, pp. 301-307.
SN	*BB	M. Mitchell, "Genetic Algorithms: An Overview," <i>Complexity</i> , 1995, Vol. 1, No. 1, pp. 31-39.

Examiner	<i>Sandy J. M.</i>	Date Considered	<i>11/08/05</i>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>		Docket Number (Optional) <b>TWI-11110</b>		Application Number <b>NEW</b>	
		Applicant(s) <b>John J. Sidorowich</b>			
		Filing Date <b>HEREWITH</b>		Group Art Unit <b>Unknown</b>	

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>SN</i>	*BC	6,532,076	03/11/2003	Sidorowich	356	630	04/04/2000

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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

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<i>SN</i>	*BD	J.R. Koza, "Introduction to Genetic Algorithms," from <i>Genetic Programming</i> , Chapter 3, pp. 17-22 and 29.
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	*BF	R.L. Riolo, "Survival of the Fittest Bits," <i>Scientific American</i> , July 1992, pp. 114-116.
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	*BI	E.A. Rietman et al., "A Genetic Algorithm for Low Variance Control in Semiconductor Device Manufacturing: Some Early Results," <i>IEEE Transactions on Semiconductor Manufacturing</i> , May 1996, Vol. 9, No. 2, pp. 223-229.
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Examiner	<i>Sangappa</i>	Date Considered	<i>11/18/05</i>
<b>Examiner:</b> Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			